

COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET PowerDI5060-8

Product Summary

Device	V _{(BR)DSS}	R _{DS(ON)}	I _D T _A = +25°C
Q1	12V	$17m\Omega$ @ $V_{GS} = 4.5V$	9.5A
		$25m\Omega$ @ $V_{GS} = 2.5V$	7.8A
Q2	-20V	32mΩ @ V _{GS} = -4.5V	-6.9A
		53mΩ @ V _{GS} = -2.5V	-5.4A

Description and Applications

This new generation Complementary Pair Enhancement Mode MOSFET has been designed to minimize R_{DS(ON)} and yet maintain superior switching performance. This device is ideal for use in Notebook battery power management and Loadswitch.

- Notebook Battery Power Management
- **DC-DC Converters**
- Loadswitch

Features and Benefits

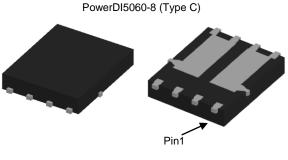
- Thermally Efficient Package-Cooler Running Applications
- High Conversion Efficiency
- Low R_{DS(ON)} Minimizes On State Losses
- Low Input Capacitance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- For automotive applications requiring specific change control (i.e.: parts qualified to AEC-Q101, PPAP capable, and manufactured in IATF 16949 certified facilities), please refer to the related automotive grade (Q-suffix) part. A listing can be found at

https://www.diodes.com/products/automotive/automotiveproducts/.

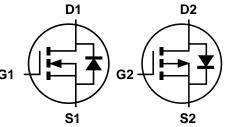
This part is qualified to JEDEC standards (as references in AEC-Q101) for High Reliability. https://www.diodes.com/quality/product-definitions/

Mechanical Data

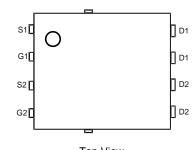
- Case: PowerDI[®]5060-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish 100% Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208 (3)
- Terminal Connections: See Diagram Below
- Weight: 0.097 grams (Approximate)







Q1 N-Channel MOSFET Q2 P-Channel MOSFET



Top View Pin Configuration

Ordering Information (Note 4)

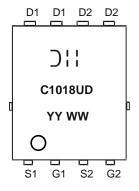
Part Number		Case	Packaging		
	DMC1018UPD-13	PowerDI5060-8 (Type C)	2500 / Tape & Reel		

Notes: 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.

- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/



Marking Information



);; = Manufacturer's Marking C1018UD = Product Type Marking Code YYWW = Date Code Marking YY = Year (ex: 15 = 2015) WW = Week (01 - 53)

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Q1 Value	Q2 Value	Units		
Drain-Source Voltage	V _{DSS}	12	-20	V		
Gate-Source Voltage	V _{GSS}	±8	±12	V		
	Steady	T _A = +25°C	I_	9.5	-6.9	А
Continuous Drain Current (Note 5) V _{GS} = 4.5V	State	$T_A = +70^{\circ}C$	ID	7.6	-5.5	
Continuous Diam Current (Note 5) VGS = 4.5V	t<10s	T _A = +25°C	I _D	13.0	-9.4	Α
	1<105	$T_A = +70$ °C		10.4	-7.5	
Maximum Body Diode Forward Current (Note 5)	I _S	2.5	-2.5	Α		
Pulsed Drain Current (10µs pulse, duty cycle = 10	I _{DM}	60	-40	Α		
Avalanche Current (Note 6) L = 0.1mH	I _{AS}	20	-17	Α		
Avalanche Energy (Note 6) L = 0.1mH	E _{AS}	25	14	mJ		

Thermal Characteristics

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)	T _A = +25°C	PD	2.3	W
Total Fower Dissipation (Note 3)	$T_A = +70$ °C	PD	1.5	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	D	54	°C/W
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	$R_{ heta JA}$	29	
Thermal Resistance, Junction to Case	R ₀ JC	6.5		
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to +150	°C

5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate. 6. I_{AS} and E_{AS} rating are based on low frequency and duty cycles to keep T_J = +25°C. Notes:



Electrical Characteristics Q1 N-Channel (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition			
OFF CHARACTERISTICS (Note 7)									
Drain-Source Breakdown Voltage	BV _{DSS}	12	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$			
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μA	$V_{DS} = 12V, V_{GS} = 0V$			
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 8V$, $V_{DS} = 0V$			
ON CHARACTERISTICS (Note 7)	ON CHARACTERISTICS (Note 7)								
Gate Threshold Voltage	V _{GS(TH)}	0.6	0.8	1.5	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$			
Static Drain-Source On-Resistance	D	_	8	17	mΩ	$V_{GS} = 4.5V, I_D = 11.8A$			
Static Diam-Source On-Nesistance	R _{DS(ON)}	_	11	25	11122	$V_{GS} = 2.5V, I_D = 9.8A$			
Diode Forward Voltage	V_{SD}	_	0.7	1.2	V	$V_{GS} = 0V, I_{S} = 2.9A$			
DYNAMIC CHARACTERISTICS (Note 8)	DYNAMIC CHARACTERISTICS (Note 8)								
Input Capacitance	C _{iss}		1525			V _{DS} = 6V, V _{GS} = 0V, f = 1.0MHz			
Output Capacitance	Coss	_	329	_	pF				
Reverse Transfer Capacitance	Crss	_	303	_					
Gate Resistance	R_{G}		1.6	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$			
Total Gate Charge (V _{GS} = 4.5V)	Q_g	_	17.1	_		V 9/1 4/94			
Total Gate Charge (V _{GS} = 8V)	Q_g	_	30.4	_	nC				
Gate-Source Charge	Qgs	_	2.6	_	110	$V_{DS} = 6V, I_{D} = 11.8A$			
Gate-Drain Charge	Q_{gd}	_	4.3	_					
Turn-On Delay Time	t _{D(ON)}	_	6.6	_		$V_{DD}=6V,\ R_L=6\Omega$ $V_{GS}=4.5V,\ R_G=6\Omega,\ I_D=1A$			
Turn-On Rise Time	t _R	_	10.8	_	ns				
Turn-Off Delay Time	t _{D(OFF)}	_	41.5	_	115				
Turn-Off Fall Time	t _F	_	21.9	_					
Body Diode Reverse Recovery Time	t _{RR}	_	14.3	_	ns	I _F = 11.8A, di/dt = 100A/μs			
Body Diode Reverse Recovery Charge	Q _{RR}		2.3	_	nC	I _F = 11.8A, di/dt = 100A/µs			

Notes: 7. Short duration pulse test used to minimize self-heating effect.

^{8.} Guaranteed by design. Not subject to product testing.



Electrical Characteristics Q2 P-Channel (@T_A = +25°C, unless otherwise specified.)

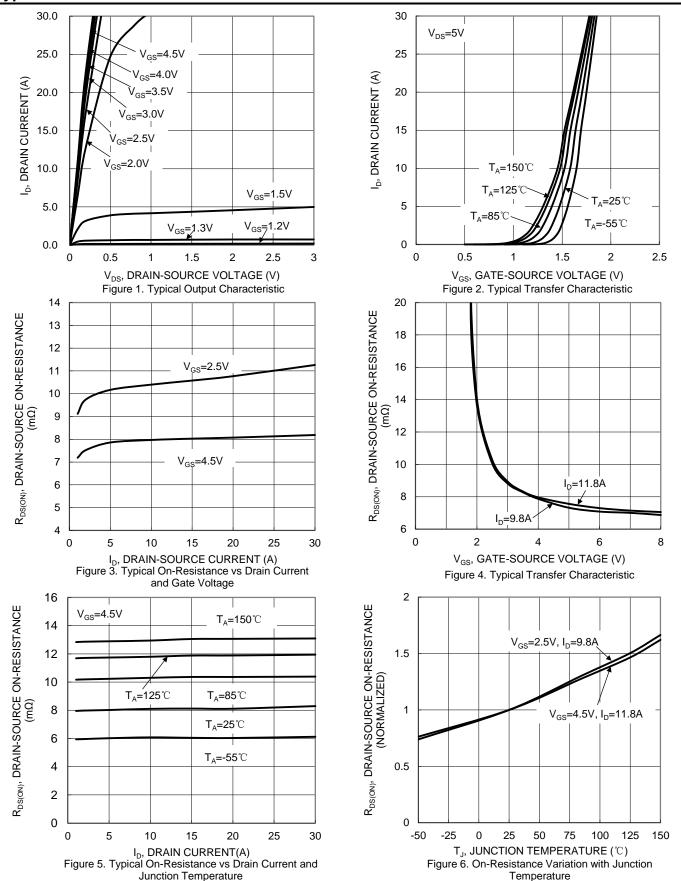
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV _{DSS}	-20	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	-1	μA	$V_{DS} = -16V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 12V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V _{GS(TH)}	-0.6	-0.8	-1.5	V	$V_{DS} = V_{GS}$, $I_D = -250\mu A$	
Static Drain-Source On-Resistance	D	_	22	32	mΩ	$V_{GS} = -4.5V, I_{D} = -8.9A$	
Static Dialif-Source Off-Resistance	R _{DS(ON)}	_	31	53	11122	$V_{GS} = -2.5V, I_D = -6.9A$	
Diode Forward Voltage	V_{SD}		-0.7	-1.2	V	$V_{GS} = 0V, I_{S} = -2.9A$	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C _{iss}		866	_		V _{DS} = -6V, V _{GS} = 0V, f = 1.0MHz	
Output Capacitance	Coss	_	167	_	pF		
Reverse Transfer Capacitance	Crss	_	131	_			
Gate Resistance	R_{G}		4.9	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	
Total Gate Charge (V _{GS} = -4.5V)	Q_g	_	8.6	_		V _{DS} = -6V, I _D = -8.9A	
Total Gate Charge (V _{GS} = -8V)	Q_g	_	19	_	nC		
Gate-Source Charge	Q_{gs}	_	1.5	_	110		
Gate-Drain Charge	Q_{gd}	_	2.5	_			
Turn-On Delay Time	t _{D(ON)}	_	5.8	_		$V_{DD} = -6V, R_L = 6\Omega$ $V_{GS} = -4.5V, R_G = 6\Omega, I_D = -1A$	
Turn-On Rise Time	t _R	_	7.7	_	ns		
Turn-Off Delay Time	t _{D(OFF)}	_	28.1	_	115		
Turn-Off Fall Time	t _F	_	14.6	_			
Body Diode Reverse Recovery Time	t _{RR}	_	9.8	_	ns	I _F = -8.9A, di/dt = -100A/μs	
Body Diode Reverse Recovery Charge	Q _{RR}		2.7	_	nC	$I_F = -8.9A$, $di/dt = -100A/\mu s$	

Notes: 7. Short duration pulse test used to minimize self-heating effect.

^{8.} Guaranteed by design. Not subject to product testing.

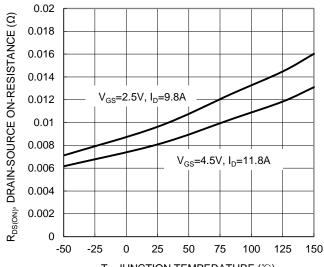


Typical Characteristics - N-CHANNEL

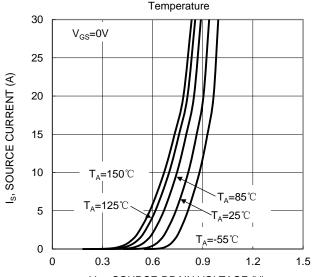




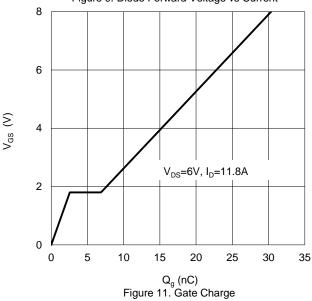




 $\mathsf{T_{J}},\mathsf{JUNCTION}$ TEMPERATURE ($^{\circ}\!\mathsf{C})$ Figure 7. On-Resistance Variation with Junction Temperature

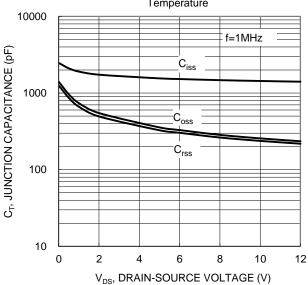


 V_{SD} , SOURCE-DRAIN VOLTAGE (V) Figure 9. Diode Forward Voltage vs Current



1.2 $V_{GS(TH)}$, GATE THRESHOLD VOLTAGE (V) 1 $I_D=1mA$ 8.0 0.6 I_D=250μA 0.4 0.2 0 -25 25 50 75 125 -50 100 150 T_J, JUNCTION TEMPERATURE (°C)

Figure 8. Gate Threshold Variation vs Junction Temperature



V_{DS}, DRAIN-SOURCE VOLTAGE (V) Figure 10. Typical Junction Capacitance

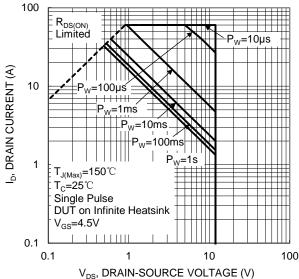
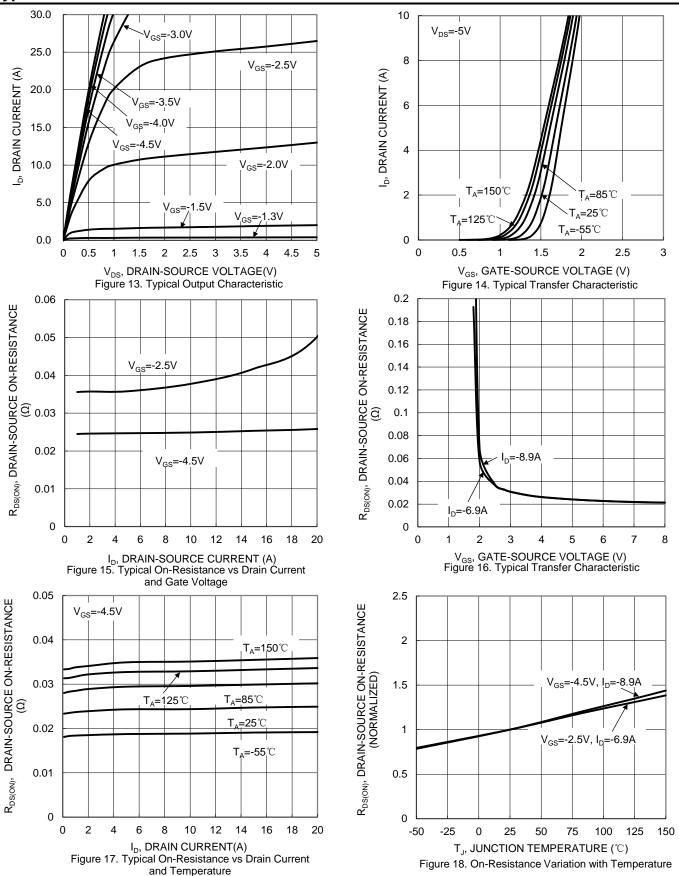


Figure 12. SOA, Safe Operation Area



Typical Characteristics - P-CHANNEL







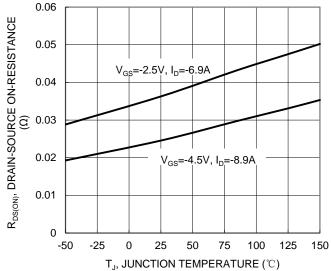
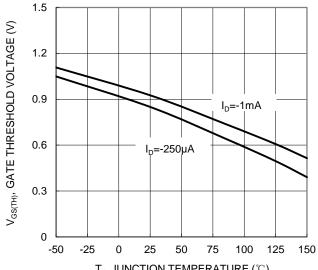
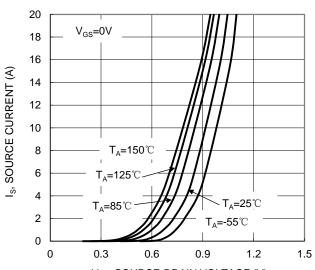


Figure 19. On-Resistance Variation with Temperature



 $T_{\rm J}$, JUNCTION TEMPERATURE (°C) Figure 20. Gate Threshold Variation vs Junction Temperature



V_{SD}, SOURCE-DRAIN VOLTAGE (V) Figure 21. Diode Forward Voltage vs Current

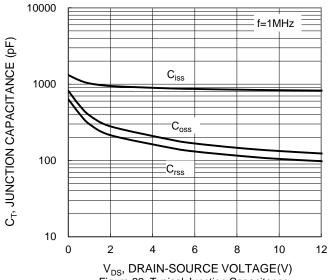
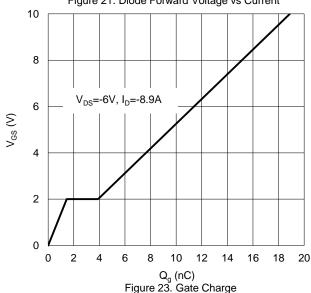
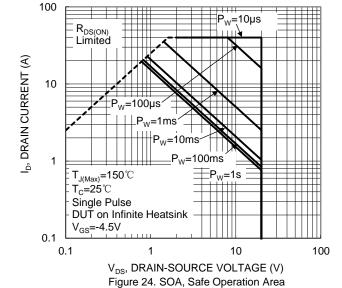


Figure 22. Typical Junction Capacitance







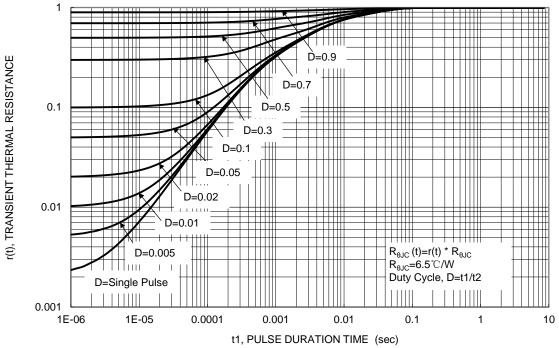


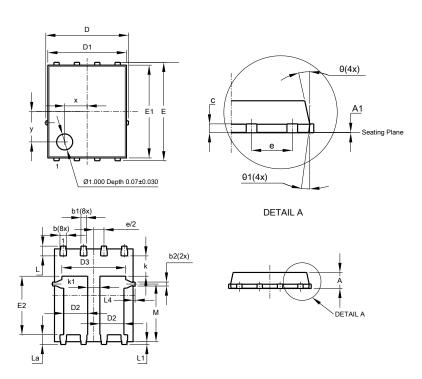
Figure 25. Transient Thermal Resistance



Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

PowerDI5060-8 (Type C)

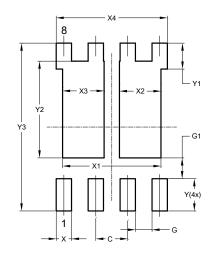


Pow	PowerDI5060-8 (Type C)						
Dim	Min	Max	Тур				
Α	0.90	1.10	1.00				
A1	0	0.05	0.02				
b	0.33	0.51	0.41				
b1	0.300	0.366	0.333				
b2	0.20	0.35	0.25				
С	0.23	0.33	0.277				
D	5	.15 BS0					
D1	4.85	4.95	4.90				
D2	1.40	1.60	1.50				
D3	-	-	3.98				
Е	6.15 BSC						
E1	5.75	5.85	5.80				
E2	3.56	3.76	3.66				
е	1.27BSC						
k	-	-	1.27				
k1	0.56	-	-				
L	0.51	0.71	0.61				
La	0.51	0.71	0.61				
L1	0.05	0.20	0.175				
L4	-	-	0.125				
М	3.50	3.71	3.605				
Х	-	-	1.400				
у	-	-	1.900				
θ	10°	12°	11°				
θ1	6°	8°	7°				
All Dimensions in mm							

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

PowerDI5060-8 (Type C)



Dimensions	Value			
Dilliensions	(in mm)			
С	1.270			
G	0.660			
G1	0.820			
Χ	0.610			
X1	3.910			
X2	1.650			
Х3	1.650			
X4	4.420			
Υ	1.270			
Y1	1.020			
Y2	3.810			
Y3	6.610			



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